



Center for **A**dvanced **M**aterials **C**haracterization in **O**regon

UNIVERSITY OF OREGON

Electron Probe Micro Analysis Worksho, September 24-26, 2003
At the MicroAnalytical Facility, 210 Cascade Hall

This is a 2 to 3 day workshop (3rd day on software issues) devoted to analytical problems in Electron Probe Micro Analysis (EPMA). Topics covered will include sensitive materials, spectral interferences, background corrections, matrix corrections, volatile elements, trace elements, thin films and particles. The guest speaker is John Armstrong of the National Institute of Standards and Technology (NIST). John has extensive background in both geology and materials and expertise in a number of electron beam techniques including microprobe x-ray analysis, scanning electron microscopy and Auger microscopy. If you have questions or for additional information, please contact John Donovan, (541) 346-4632 or e-mail at donovan@oregon.uoregon.edu.

Additional information will be sent out to all attendees. Registration Fee: **\$400.00** for commercial and for-profit attendees or **\$100.00** for academic or non-profit attendees and includes all workshop materials.

Registration Form:

Name: _____

Company: _____

Street Address: _____

City, State, ZIP: _____

Telephone Number: _____

FAX #: _____

E-mail Address: _____

Circle the days you plan to attend: 9/24 (Wednesday) 9/25 (Thursday) 9/26 (Friday)

Checks Payable to: University of Oregon

Mail or FAX to: John Donovan, MicroAnalytical Workshop (541) 346-4692
Department of Geological Sciences
1272 University of Oregon
Eugene, OR 97403-1272

Sorry we cannot take credit cards, however if you cannot generate a check for the registration fee we might be able to invoice you for the amount. Please contact me to discuss this latter option.